Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/550,393	CHEN ET AL.
Examiner	Art Unit
Karuna B. Baddu	1712

SEARCHED				
Subclass	Date	Examiner		
543	11/8/2006	KR		
261	11/8/2006	KR		
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	Subclass 543	Subclass Date 543 11/8/2006 261 11/8/2006		

INTERFERENCE SEARCHED				
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EAST, Inventor Search PALM	11/8/2006	KR
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